**Background:** Internet of Things (IoT)  
Sensor interface analog circuit is a key.

**Requirement:** High reliability

**Challenge:**  
Their production testing with high quality, low cost

**Research target:**  
Short time testing of high resolution, low speed analog-to-digital converter (ADC)

**Our approach:**  
Consideration of ADC internal circuit.  
Finding of error prone codes and careful testing.

We have developed its effective testing algorithms